

**RESPONSE UNDER 37 C.F.R. §1.116**  
**EXPEDITED PROCEDURE - EXAMINING GROUP 2800**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

*OK 8/25/07*

In re Application	)	<b><u>PATENT APPLICATION</u></b>
Inventors: Frederick Ware, et al.	)	
Application No.: 10/768,443	)	Art Unit: 2829
Filed Date: Jan. 30, 2004	)	Examiner: Nguyen, T.
Title: METHOD AND APPARATUS FOR TEST CHARACTERIZATION OF SEMICONDUCTOR COMPONENTS	)	Customer No.: 38456

**RESPONSE TO OFFICE ACTION UNDER 37 C.F.R. §1.116**

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This RESPONSE is in reply to the outstanding Office action.

**AMENDMENTS to the CLAIMS** begin on Page 2 of this RESPONSE.

**REMARKS** begin on Page 28 of this RESPONSE.